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(54) Title (EN): MAP CALIBRATION METHOD, MOBILE TERMINAL FOR SURVEYING AND MAPPING, AND SURVEYING AND MAPPING SYSTEM

(54) Title (FR): PROCÉDÉ D'ÉTALONNAGE DE CARTE, TERMINAL MOBILE POUR ARPENTAGE ET CARTOGRAPHIE, ET SYSTÈME D'ARPENTAGE ET DE CARTOGRAPHIE

(54) Title (ZH): 地图校准方法、测绘移动终端以及测绘系统

(57) Abstract:

(EN): A map calibration method, a mobile terminal for surveying and mapping, and a surveying and mapping system. The map calibration method comprises: obtaining position information of n surveying and mapping points (101); calculating to obtain position information of a map point on an electronic map corresponding to a surveying and mapping point so as to generate a matching pair (102); generating, according to the matching pair, a calibration relationship between the position information of the surveying and mapping point and the position information of the map point (103); and obtaining, according to the calibration relationship, a calibrated map point (104).

(FR): Cette invention concerne un procédé d'étalonnage de carte, un terminal mobile pour arpentage et cartographie, et un système d'arpentage et de cartographie. Le procédé d'étalonnage de carte comprend les étapes consistant à : obtenir des informations de position de n points d'arpentage et de cartographie (101) ; calculer pour obtenir des informations de position d'un point de carte sur une carte électronique correspondant à un point d'arpentage et de cartographie de façon à générer une paire d'appariement (102) ; générer, suivant la paire d'appariement, une relation d'étalonnage entre les informations de position du point d'arpentage et de cartographie et les informations de position du point de carte (103) ; et obtenir, suivant la relation d'étalonnage, un point de carte étalonné (104).

(ZH): 一种地图校准方法、测绘移动终端以及测绘系统,地图校准方法包括获取n个测绘点的位置信息(101);在电子地图上计算获得与测绘点相对的地图点的位置信息,以生成匹配对(102);根据匹配对生成测绘点和地图点的位置信息的校准关系(103);根据校准关系得到校准后的地图点(104)。

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